## Special Issue

## Photoionization Mass Spectrometry

## Message from the Guest Editor

Mass spectrometry is widely used for the measurement of organic compounds. For example, persistent organic pollutants (POPs) in the environment have been successfully measured at trace levels. Currently, an electron ionization source is utilized in mass spectrometry. This approach, however, suffers from several limitations: It is sometimes difficult to observe a molecular ion, which prevents the determination of a molecular weight. When a light is used as the ionization source, it is possible to solve some parts of these problems. There are many approaches of using a laser emitting from the vacuum-ultraviolet to infrared regions, from the femtosecond to nanosecond lasers, and for the gaseous-phase to solid-phase samples. In this Special Issue, the welcomes the submission of papers related to state-of-the-art technology of "Photoionization Mass Spectrometry", not only for basic science, but also for practical applications, such as in environmental and forensic sciences.

### **Guest Editor**

Prof. Dr. Totaro Imasaka Professor Emeritus, Kyushu University, Fukuoka 819-0395, Japan

## Deadline for manuscript submissions

closed (15 July 2018)



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## Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multidimensional network.

## Editor-in-Chief

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